

Session FF

Applications of Measurement Technology

Chairman:

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The development of sophisticated measurement technology has largely been driven by application requirements. By exploiting the unique advantages of microwaves with computers, an enhanced level of sensitivity and accuracy is obtained. This session covers the full microwave spectrum from RF to millimeter and quasi-optics. The papers include sensing systems for environmental characterizations such as distance, temperature and material properties as well as the more traditional noise and S-parameter measurements.

**8:30 a.m.–10:00 a.m., Thursday, June 13, 1991
Room 302**

